

**Notice of References Cited**Application/Control No.  
**09/975,544**Applicant(s)/Patent Under Reexam  
**Hanson et al.**Examiner  
**David L. Lewis**Art Unit  
**2673**

Page 1 of 1

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	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
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